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## Test Configuration:

Num	Item	Spec
1.	<b>Operator Panel:</b>	TF-ONYX-154HT-A1-1110
	1.LCD	15" CPT CLAA150XP07FQ
	2. Power Supply	Astordyne ASM-150-24
	4. Inverter	HWA YOUN QF132v1.16
2.	<b>CPU Board:</b>	EMB-852T Rev: A1.1
	1. Bios Ver.	ONYX-154 A0.2
	2.CPU	Intel Pentium-M Processor 1.6GHz
	3.Memory	DSL 512MB / Hynix HY5DU121622CTP-J
	4. HDD	FUJITSU MHW2040AT / 40GB
	5.Test Software	Windows XP / Run PassMark Burn In Test 5.1 Pro

## CPU Cooler



# Temperature cycle test

**Test Date:** 05-27~30-2008

**Test Product:** ONYX-154

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

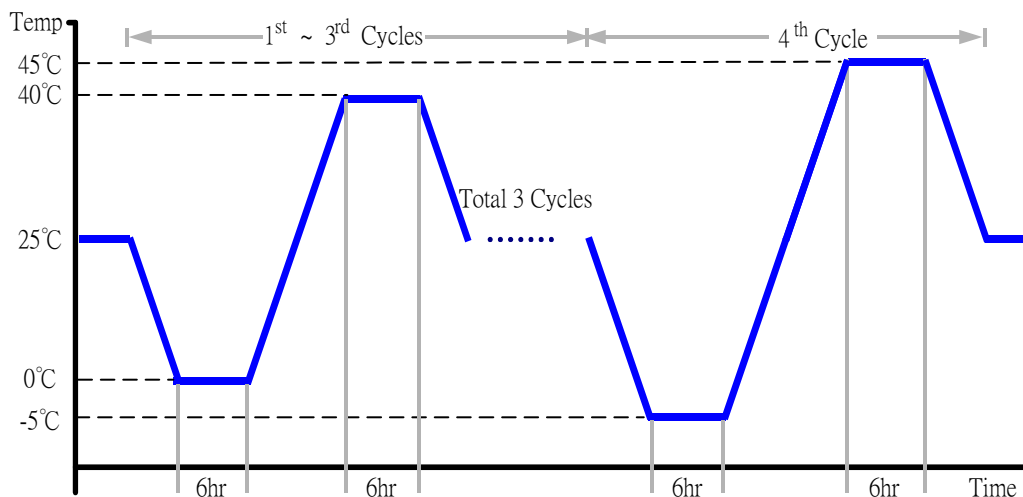
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 05/16/07  
Serial Number: 1241

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/13/07  
Serial Number: 12A323190

**Test Condition:**

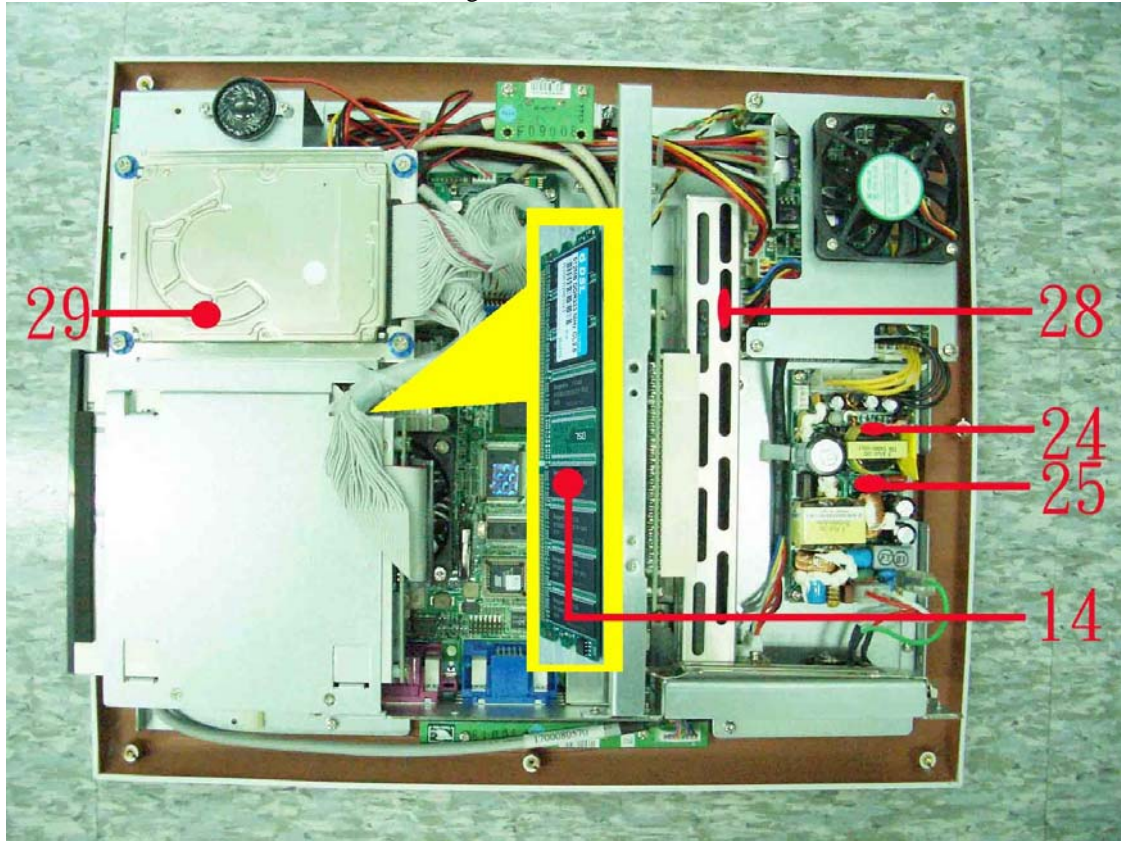
1. Test Low Temperature: 0°C (1~3 cycles)  
-5°C (4<sup>th</sup> cycle)
2. Test High Temperature: 40°C (1~3 cycles)  
45°C (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



# Temperature cycle test

## Terminal Recorder:

Measuring Accelerometer Position



# Temperature cycle test

Thermal profile data:

## ONYX-154

Point	Temp. Stage(°C)	Spec	40	25	0
<b>EMB-852T</b>					
01. CPU		100	82.8	67.8	42.8
02. U24-Chipset.NB82852GM.Intel.RG82852GM		105	78.4	63.4	38.4
03. U25-Chipset ICH4.INTEL.FW82801DB		110	76.8	61.8	36.8
04. U54-ACPI Power Controller.Intersil.ISL6506BCB		100	70.3	55.3	30.3
05. U10-N-Channel.30V.10A.13.5mΩ .MOSFET.APEC.AP4410M		125	72.5	57.5	32.5
06. L2- INDUCTOR.3.3uH.20%. VISHAY.IHLP2525CZRZ3R3M01		125	73.5	58.5	33.5
07. U11-Step-Down DC/DC Controller.Anpec.APW7057		100	73.4	58.4	33.4
08. U57-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	73.4	58.4	33.4
09. U22-CLOCK GENERATOR.ICS.ICS952601		115	84.0	69.0	44.0
10. U45-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	67.9	52.9	27.9
11. U44-(TF)RS232 Driver ESD 15KV.INTERASIL.HIN213ECAZ		70	68.4	53.4	28.4
12. TC25-220uF.2V.Panasonic.EEFSX0D221YR		105	77.3	62.3	37.3
13. TC27-150uF.6.3V.Panasonic.ECGUD0J151R		105	79.2	64.2	39.2
14. Memory		70	67.9	52.9	27.9
<b>PER-P12D A02</b>					
15. L2 - (TF)COIL.3.3uH.GOTREND.GSTC135P-3R3MF		125	78.7	63.7	38.7
16. L3 - (TF)COIL.2.2uH.GOTREND.GSTC135P-2R2MF		125	75.5	60.5	35.5
17. U4 - (TF) Regulator.Vin 3.5-36V.LINEAR.LTC3728EUH#PBF		85	69.0	54.0	29.0
18. L7 - (TF)COIL.33uH.GOTREND.GDO-0804-P-330-M		85	60.3	45.3	20.3
19. D11 - (TF) D Schottky.60V.3A.SMD.WILLAS.SK36C-TG		125	60.4	45.4	20.4
20. T2 - (TF)POWER MOSFET.SMD.SO-8.International Rectifier.IRF7416PbF		125	61.1	46.1	21.1
21. U6 - (TF) Lithium-Ion Battery.Charger.LINEAR.LTC4007EGN#PBF		85	58.3	43.3	18.3
22. T3 - (TF)POWER MOSFET.SMD.SO-8.International Rectifier.IRF7416PbF		125	67.3	52.3	27.3
23. D10 - (TF)D Schottky.SMC.Power Rectifier.ON.MBRS330T3G		100	61.4	46.4	21.4
<b>Power</b>					
24. T1		125	72.9	57.9	32.9
25. Q5		105	81.2	66.2	41.2
<b>Inverter</b>					
26. IC1		85	69.1	54.1	29.1
27. Q2		150	73.0	58.0	33.0
<b>28. Battery</b>		55	59.7	44.7	19.7
<b>29. HDD</b>		60	54.7	39.7	14.7
30. Control Box Surface		N/A	50.4	35.4	10.4
31. Chamber Air Temperature		N/A	41.0	26.0	1.0

# Temperature cycle test

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## Sample Configuration & Quantity Under Test:

Quantity: 1 (ONYX-154)

## Test Result:

No problem was found during the temperature operation cycle test.

**Test Date:** 05-19~21-2008

**Test Product:** ONYX-154

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 05/16/07  
Serial Number: 1241

**Testing Item:**

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (ONYX-154)

**Test Result:**

No problem was found after the high temperature storage test.

# Low temperature storage test

**Test Date:** 05-16~19-2008

**Test Product:** ONYX-154

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 05/16/07  
Serial Number: 1241

**Testing Item:**

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (ONYX-154)

**Test Result:**

No problem was found after the low temperature storage test.



**Test Date:** 05-12~15-2008

**Test Product:** ONYX-154

**Test Site:** AAEON QA Internal Lab.

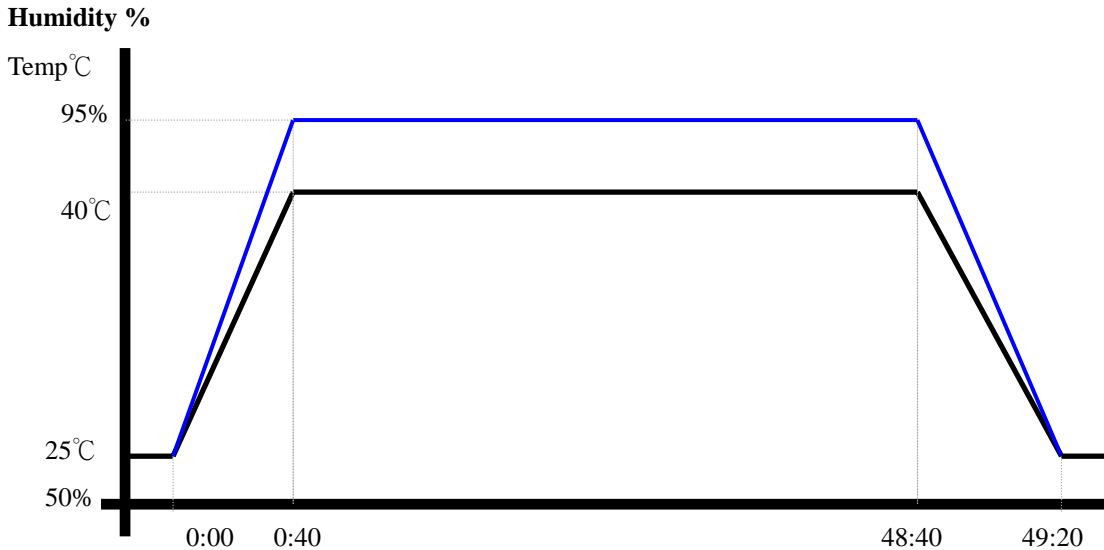
**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 05/16/07  
Serial Number: 1241

**Testing Item:**

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (ONYX-154)

**Test Result:**  
No problem was found after the humidity storage test.

# Cold start and hot start test

**Test Date:** 05-15~16-2008

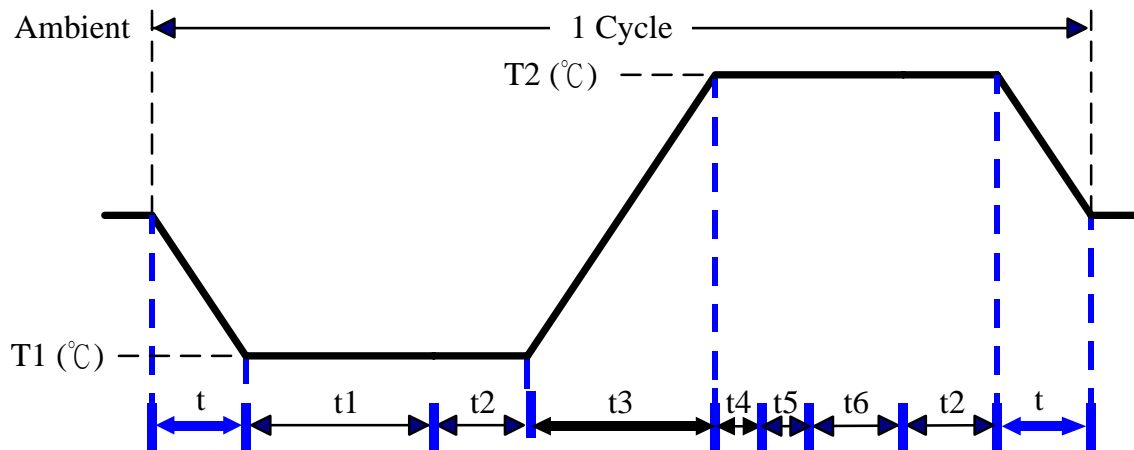
**Test Product:** ONYX-154

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 05/16/07  
Serial Number: 1241

**Test Condition:**



Parameters	Description
T1	-5°C
T2	45°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope  
t , t1, t6: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3, t4: Run PassMark Burn In Test  
t5: Win XP Software restart test 3 times  
Test Software: Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.